

## Q. Metrology, Inspection, and Yield Enhancement 분과

2020년 2월 14일(금), 09:00-10:30 / Room H (하트 I, 6층)

### ■ [FH1-Q] Nanoanalysis and Characterization

좌장: 정용우 박사 (SK하이닉스), 조용재 박사 (한국표준과학연구원)

<b>FH1-Q-1</b> <b>09:00-09:30</b>	<p>[초청]</p> <p><b>Spectroscopic Ellipsometric Study on Temperature Dependence Dielectric Functions and Critical Point Energies for 2D Materials</b></p> <p>Tae Jung Kim<sup>1</sup>, Hoang Tung Nguyen<sup>1</sup>, Van Long Le<sup>1</sup>, Xuan Au Nguyen<sup>1</sup>, Do Hyoung Koo<sup>2</sup>, Chul-Ho Lee<sup>2</sup>, Farman Ullah<sup>3</sup>, Yong Soo Kim<sup>3</sup>, and Young Dong Kim<sup>1</sup></p> <p><sup>1</sup>Department of Physics, Kyung Hee University, <sup>2</sup>KU-KIST Graduate School of Converging Science &amp; Technology, Korea University, <sup>3</sup>Department of Physics and Energy Harvest Storage Research Center (EHSRC), University of Ulsan</p>
<b>FH1-Q-2</b> <b>09:30-10:00</b>	<p>[초청]</p> <p><b>Redefinition of kg Using Kibble Balance and its Application in Semiconductor Metrology</b></p> <p>Dongmin Kim</p> <p>KRISS</p>
<b>FH1-Q-3</b> <b>10:00-10:30</b>	<p>[초청]</p> <p><b>Confocal Thermo-Reflectance Microscope and Applications</b></p> <p>Ki Soo Chang<sup>1</sup>, Dong Uk Kim<sup>1</sup>, Chan Bae Jeong<sup>1</sup>, Ilkyu Han<sup>1</sup>, Jung Dae Kim<sup>1</sup>, Hyun Hwangbo<sup>1</sup>, Seung-Woo Lee<sup>2</sup>, and Byung-Seon Chun<sup>2</sup></p> <p><sup>1</sup>Division of Scientific Instrumentation, KBSI, <sup>2</sup>Nanoscope Systems, Inc.</p>